Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/703,792	HAYAKAWA ET AL.	
Examiner	Art Unit	
CHUONG T. HO	2616	_

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Class	Subclass	Date	Examiner
370	229 231	09/25/06	OH
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/703,792	HAYAKAWA ET AL.
Examiner	Art Unit
CHUONG T. HO	2616

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Class	Subclass	Date	Examiner
370	516	09/26/06	CH
370	517		
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370	525	<u> </u>	<u> </u>

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